

March 23, 2005

RE: FCC ID: PPIRM-94_ATCB002213
Attention: Dennis Ward

Following answers regarding your questions of March 16, 2005:

1. Block diagram for part 15 device

Block diagram updated with frequency information.

2. Reference in BT report

The reference was incorrect. We confirm, that the measurement procedures have been in accordance to the 2003 version of the ANSI C63.4. BT report updated accordingly.

3. Dwell information in BT report

Report updated with consistent dwell time information.

4. Formula part 24 report

Report updated with correct substitution correction formula.

5. EIRP

As the device does not have a coaxial RF connector, it was not possible to make a conducted measurement of the output power. As a result, only radiated power levels can be measured. The same sample was used for EIRP and SAR measurements.

The EIRP was measured by Nokia TCC EMC lab in Salo, Finland after completion of SAR measurements. No power measurements were made by Nokia TCC SAR lab because the SAR lab is not able to measure radiated power. The product was not reconfigured between EMC and SAR tests and was hand-carried between the EMC and SAR labs, which are both located in Salo, Finland. The power settings are stored in digital memory and were the same for EMC and SAR tests.

6. Statement for part 15C device:

User guide updated.

7. Probe Calibration

The +/-9.7% uncertainty quoted in the calibration data is a k=2 value i.e. it is equal to 2 x standard deviation. The +/-5.8% value given in the measurement uncertainty table in Section 6 of the SAR report is 1 x standard deviation only. The magnitude of 5.8 is sufficient to cover all of our measurement probes and leads to a slightly conservative estimate for the overall measurement uncertainty of the test equipment used for SAR tests on this product.